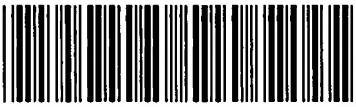


<b>Search Notes</b> 	<b>Application/Control No.</b> 10530572	<b>Applicant(s)/Patent Under Reexamination</b> REIFFENRATH ET AL.
	<b>Examiner</b> Cho, Jennifer Y	<b>Art Unit</b> 1621

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STN Search	7/3/07	KS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner